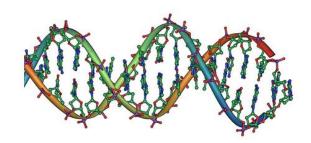


# IP MARKETPLACE

CONNECTING INNOVATION TO YOUR BUSINESS

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### METHOD AND APPARATUS FOR PROFILING DNA SPECIMEN



## MORE INFORMATION

#### **MEGA-TREND**

- Innovative Technologies of the Future
- Healthcare

## **TECHNOLOGY READINESS LEVEL (TRL)**

TRL 3 (Proof of Concept)

## PATENT/ GRANTED NUMBER

PI 2015703987



## **TECHNOLOGY OVERVIEW**

Novel method and apparatus for profiling dna specimen using electronics is described. The method comprises: providing a metal layer; providing a dna specimen layer adjacent to metal layer to form schottky junction; providing forward bias voltage to the schottky junction and collecting current over voltage (i-v) profile of schottky junction. I-v profile of various dna can be collected to build a dna database. This database can be used to identify unknown dna specimen. An apparatus is provided to profile dna specimen comprising: metal layer; the dna specimen adjacent to metal layer to form schottky junction, a forward bias voltage provider rectifies the schottky junction and a monitor collects current over voltage profile of schottky junction.

## **CONTACT US!**

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